

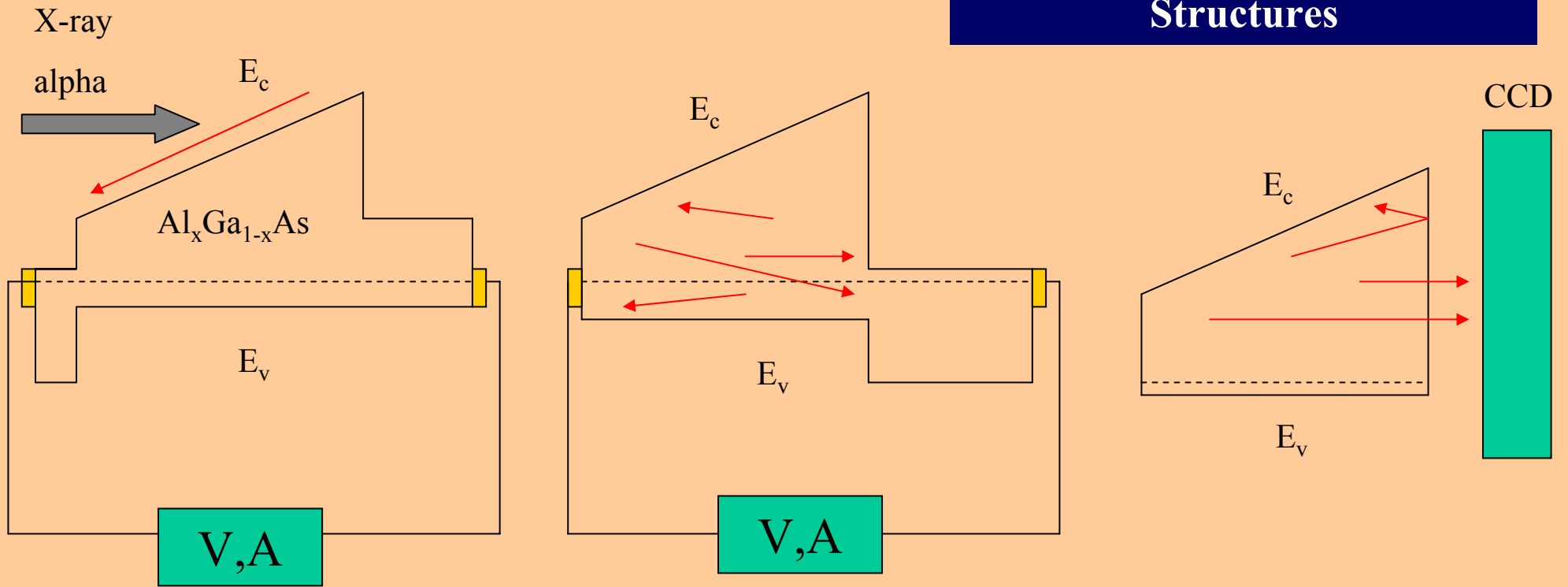
Radiation hardness of graded-gap AlGaAs X-ray detectors

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Structures



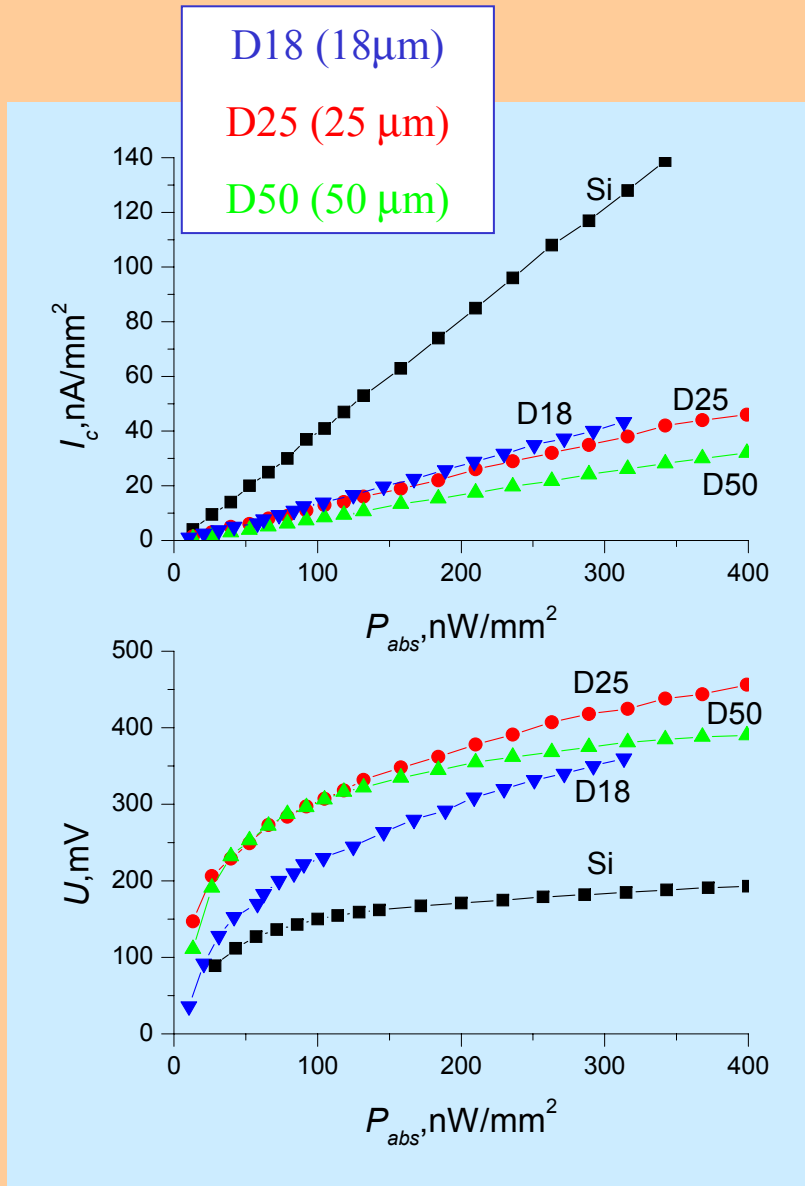
$$\beta = \frac{\tau_{rec}}{t_{dr}}$$

$$\tau_{rec} = \tau_r + \tau_{nr}$$

$$\eta = \frac{1}{1 + \tau_r / \tau_{nr}}$$

$$\eta_{ef} = \frac{1}{2} \eta \left(1 + \frac{1}{2} \eta + \frac{1}{4} \eta^2 + \dots \right)$$

Current and voltage response



$$I_{ph} = \frac{P_{abs}}{E_{th}} \eta_{ef}$$

$$I_{max} = 0.25 P_{abs}$$

$$U = \frac{kT}{q} \ln \frac{I_s + I_{ph}}{I_s}$$

D18, D25
 $\beta_I \approx 0,13 \text{ A/W}$ $\eta_{ef} \approx 0,52$

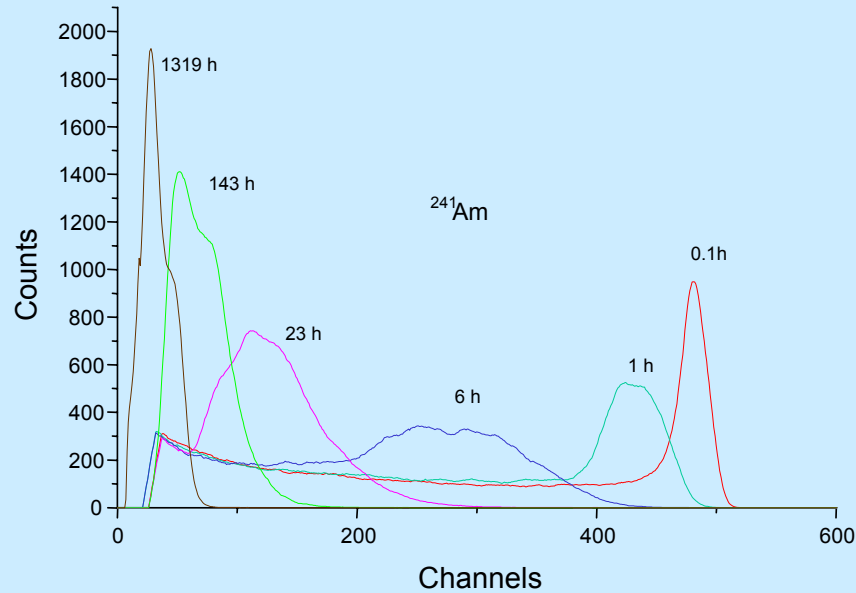
D50
 $\beta_I \approx 0,07 \text{ A/W}$ $\eta_{ef} \approx 0,27$

β_I - current sensitivity
 η_{ef} - quantum efficiency

$\beta_v > 10^6 \text{ V/W}$
 $P_{abs} = 50 \text{ nW/mm}^2$

Cu anode $E = 8 \text{ keV}$

Alpha particle spectrum



^{241}Am $E = 5.48\text{MeV}$

$1\text{h} \rightarrow 10^8 \text{ particles/cm}^2$

$$\frac{a_\alpha}{a_0} = \frac{\tau_{rec}}{t_{dr}} [1 - \exp(-t_{dr} / \tau_{rec})]$$

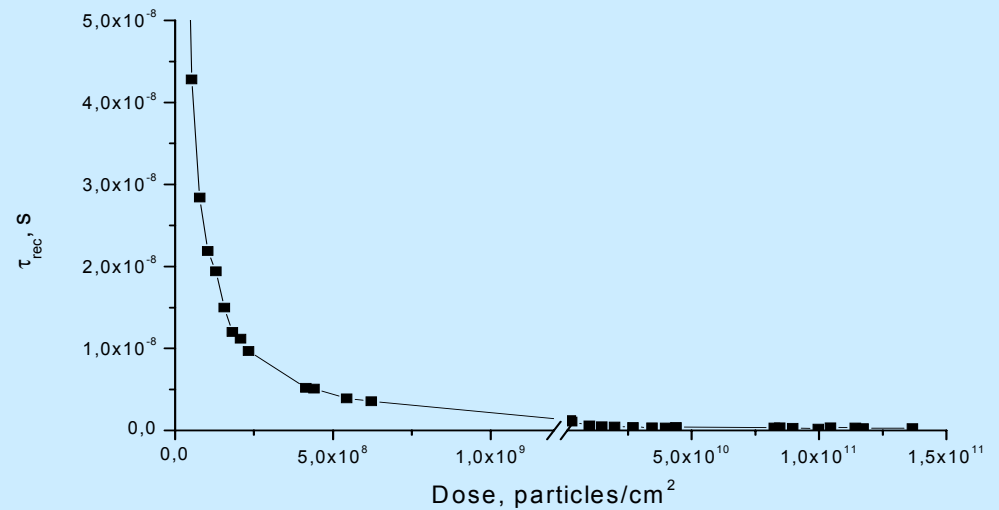
$l = 25\mu\text{m},$

$E = 120 \text{ V/cm}, t_{dr} \approx 5\text{ns}$ if $\tau_{rec} = 10^{-8}\text{s}$

CCE $\rightarrow 100\%$

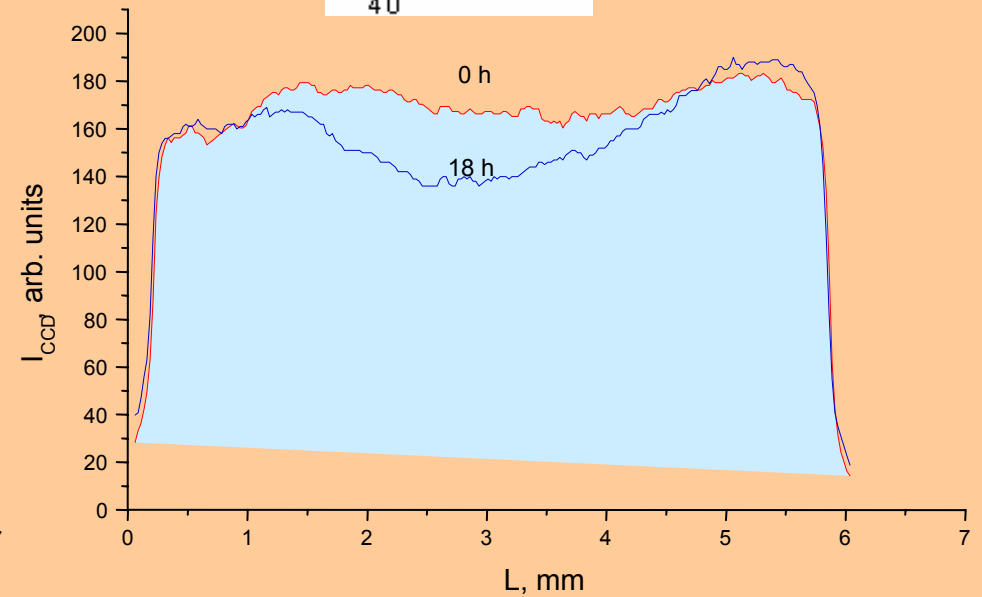
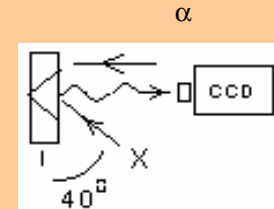
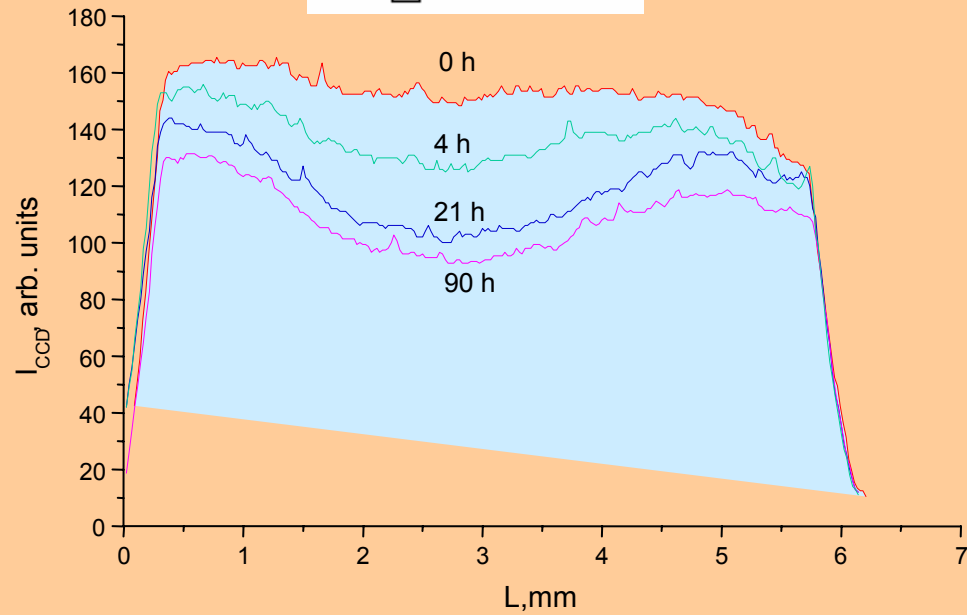
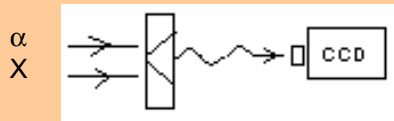
Decrease of current response about an order

Confirmed by 8 keV X-ray measurement



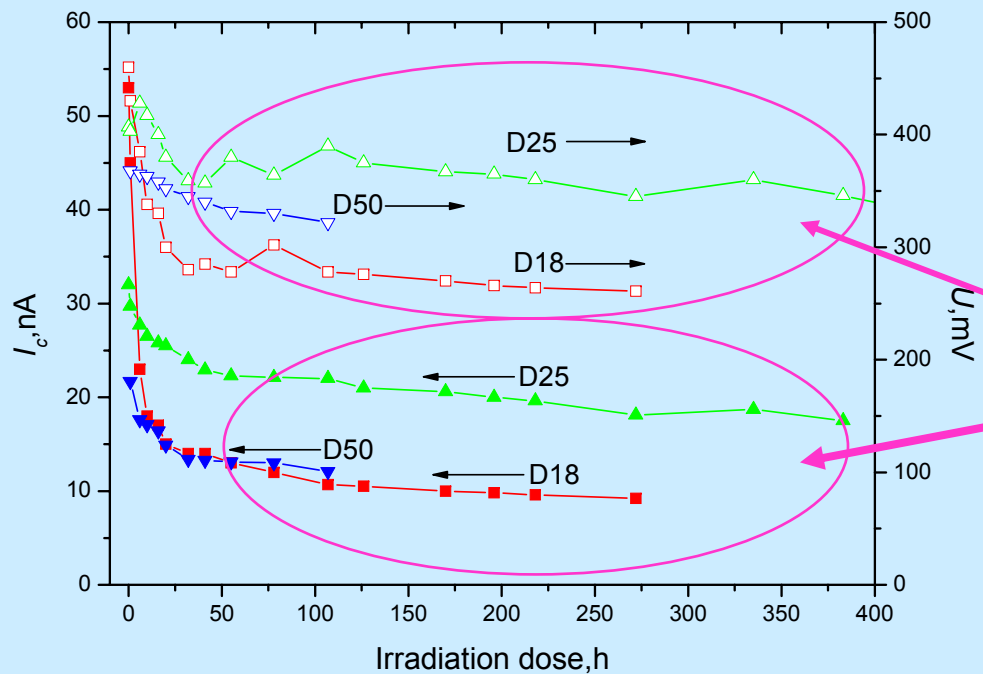
Optical response

$$S = 5 \times 6 \text{ mm}^2$$



Decrease of optical response about 1.5 times

Defects generated by alpha particles are not only non-radiative but also radiative recombination centers

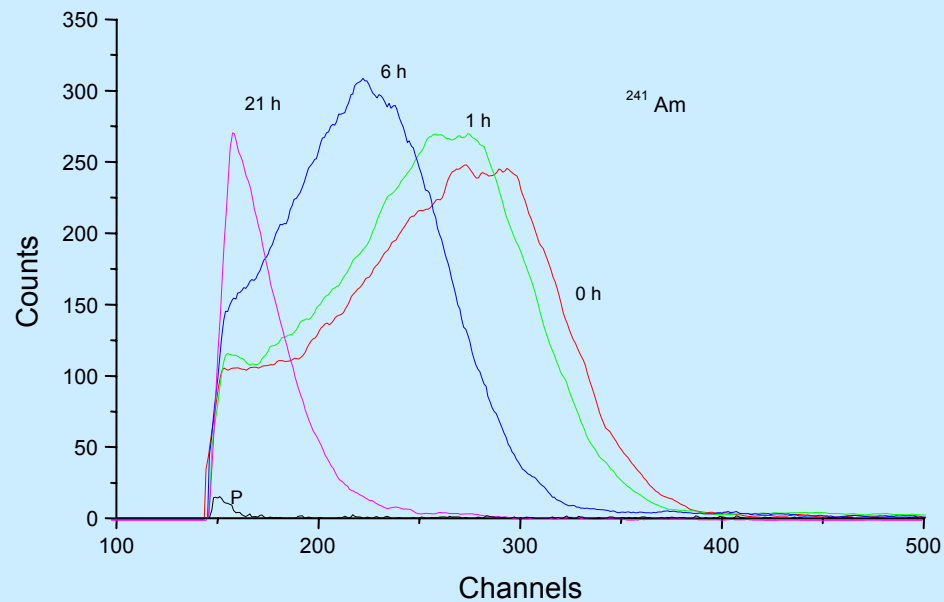


Internal optical response

Response remains nearly constant when irradiation dose larger than $5 \cdot 10^9$ particles/cm²

The decrease of response at small irradiation dose is less significant for thick samples (D25 and D50) when penetration depth of alpha particle is less than distance to p-n junction.

Penetration depth of alpha particle in GaAs is about 20 μm



Conclusions

Decrease of current response under alpha particle irradiation (about an order at irradiation dose 10^{10} particles/cm²) is caused by growth of recombination rate.

The much better alpha particle irradiation hardness (decrease of detector sensitivity about 1.5 times at irradiation dose $5 \cdot 10^9$ particles/cm²) is obtained for detectors with optical response.

The internal quantum efficiency of the X-ray conversion to light remains almost constant because the increase of the non-radiative recombination rate is compensated by **increase of radiative recombination rate**.

The best alpha particle irradiation hardness is obtained for detectors made on base of structure p -Al_xGa_{1-x}As – n -GaAs with p-n junction in the wide gap side, when thickness of graded-gap Al_xGa_{1-x}As layer is larger than alpha particle penetration length.

Increase of radiative recombination rate have to determine high operating speed .

This work was supported by
Lithuanian State Science and Studies foundation